Ultramicroscopy 45 (1992) 431–433
North-Holland

ultramicroscopy

Author index to volume 45

Adamchuk, V.K. and A.V. Ermakov, Device for direct writing and reading-out of information based on the scanning tunneling microscope 45 (1992) 1
Astl, G., see Mayer 45 (1992) 185

Ballongue, P., see Jeanguillaume 45 (1992) 205
Barrachina, R.O. and A. Gras-Marti, Note on the energy lost by a charged particle specularly reflecting at a surface 45 (1992) 345
Bird, D.M. and M. Saunders, Sensitivity and accuracy of CBED pattern matching 45 (1992) 241

Chu, Y.M., see Wang 45 (1992) 405
Colliex, C., see Jeanguillaume 45 (1992) 205
Cowley, J.M., see Tsai 45 (1992) 43
Cowley, J.M., see Tsai 45 (1992) 55
Cowley, J.M., see Gribelyuk 45 (1992) 103
Cowley, J.M., see Gribelyuk 45 (1992) 115
Cullis, A.G., see Nakahara 45 (1992) 365

D'Antonio, P., see Konnert 45 (1992) 281
De Graef, M., see Janssens 45 (1992) 323
Dorset, D.L., Direct phasing in electron crystallography: determination of layer silicate structures 45 (1992) 5
Dorset, D.L., W.F. Tivol and J.N. Turner, Electron crystallography at atomic resolution: ab initio structure analysis of copper perchlorophthalocyanine (*Erratum*) 45 (1992) 165
Dorset, D.L., Automated phase determination in electron crystallography: thermotropic phases of thiourea 45 (1992) 357
Duan, X.F., see Wang 45 (1992) 405

Ermakov, A.V., see Adamchuk 45 (1992) 1

Fink, H.-W., see Kreuzer 45 (1992) 381
Fujiyoshi, Y., see Sakata 45 (1992) 253

Gallerneault, C., see Timsit 45 (1992) 65
Geipel, T. and M. Hohenstein, Analytical description of image contrast in HRTEM and applications 45 (1992) 167
Gras-Marti, A., see Barrachina 45 (1992) 345
Gribelyuk, M.A. and J.M. Cowley, Computer analysis of side-band holography in STEM 45 (1992) 103
Gribelyuk, M.A. and J.M. Cowley, Determination of the imaging conditions in off-axis side-band STEM holography 45 (1992) 115
Gribelyuk, M.A. and J.L. Hutchison, On the iterative restoration of the exit plane wave function from defocus series in HREM 45 (1992) 127
Gutakovsky, A.K., see Sabinina 45 (1992) 411

Haga, Y. and K. Takayanagi, Single atom imaging in high-resolution UHV electron microscopy: Bi on Si(111) surface 45 (1992) 95
Hashimoto, H., see Li 45 (1992) 299
Hawkes, P.W., Novelties for the bookshelves 45 (1992) 421
Hoffmann, H., see Mändl 45 (1992) 351
Hohenstein, M., see Geipel 45 (1992) 167
Horita, Z., M.R. McCartney and J.K. Weiss, Computer-assisted extrapolation method for absorption correction in quantitative X-ray microanalysis 45 (1992) 263
Huang, D.X., see Li 45 (1992) 299
Hutchison, J.L., see Gribelyuk 45 (1992) 127

Janssens, K.G.F., J. Vanhellemont, M. De Graef and O. Van der Biest, SIMCON: a versatile software package for the simulation of electron diffraction contrast images of arbitrary displacement fields 45 (1992) 323
Jeanguillaume, C., C. Colliex, P. Ballongue and M. Tencé, New STEM multisignal imaging modes, made accessible through the evaluation of detection efficiencies 45 (1992) 205

Khiznichenko, V., see Tsai 45 (1992) 55
Kimura, Y., see Sakata 45 (1992) 253
Konnert, J. and P. D'Antonio, Simulation and interpretation of STEM side-band holograms 45 (1992) 281
Krakow, W., Sideband holographic imaging of a tilt grain boundary to the 1.22 Å resolution level 45 (1992) 269
Kreuzer, H.J., K. Nakamura, A. Wierzbicki, H.-W. Fink and H. Schmid, Theory of the point source electron microscope 45 (1992) 381

Lehmpfuhl, G., see Wang 45 (1992) 291
Lenc, M. and I. Müllerová, Optical properties and axial aberration coefficients of the cathode lens in combination with a focusing lens 45 (1992) 159

Elsevier Science Publishers B.V.

Leonard, K.R., see Trachtenberg 45 (1992) 307
Li, F.H., G.Z. Pan, D.X. Huang, H. Hashimoto and Y. Yokota, Phason-strain identification for quasicrystals by high-resolution electron microscopy 45 (1992) 299

Mändl, M., J. Zweck and H. Hoffmann, Method for detection of thermally activated element migration inside multilayer metallizations by means of electron microscopy 45 (1992) 351
Marks, L.D., Registry and UHV transmission electron diffraction of surfaces 45 (1992) 145
Marks, L.D., see Xu 45 (1992) 155
Matteucci, G., G.F. Missiroli, M. Muccini and G. Pozzi, Electron holography in the study of the electrostatic fields: the case of charged microtips 45 (1992) 77
Mayer, E. and G. Astl, Limits of cryofixation as seen by Fourier transform infrared spectra of metmyoglobin azide and carbonyl hemoglobin in vitrified and freeze-concentrated aqueous solution 45 (1992) 185
McCallum, B.C. and J.M. Rodenburg, Two-dimensional demonstration of Wigner phase-retrieval microscopy in the STEM configuration 45 (1992) 371
McCartney, M.R., see Horita 45 (1992) 263
Missiroli, G.F., see Matteucci 45 (1992) 77
Möllenstedt, G., see Zhou 45 (1992) 163
Morikawa, K., see Sakata 45 (1992) 253
Morniroli, J.P. and J.W. Steeds, Microdiffraction as a tool for crystal structure identification and determination 45 (1992) 219
Moskovits, M., see Wang 45 (1992) 337
Muccini, M., see Matteucci 45 (1992) 77
Müllerová, I., see Lenc 45 (1992) 159

Nakahara, S. and A.G. Cullis, Simple method for determining the absolute sense of image rotation in a transmission electron microscope 45 (1992) 365
Nakamura, K., see Kreuzer 45 (1992) 381

Pan, G.Z., see Li 45 (1992) 299
Peng, L.-M., see Wang 45 (1992) 405
Pozzi, G., see Matteucci 45 (1992) 77

Rodenburg, J.M., see McCallum 45 (1992) 371
Rowntree, P., see Wang 45 (1992) 337

Sabinina, I.V. and A.K. Gutakovsky, Preparation of TEM samples from compound semiconductors by chemomechanical polishing 45 (1992) 411
Sakata, K., Y. Tahara, K. Morikawa, Y. Fujiyoshi and Y. Kimura, A method for observing cross-sectional views of biomembranes 45 (1992) 253
Saunders, M., see Bird 45 (1992) 241
Schatz, M. and M. van Heel, Invariant recognition of molecular projections in vitreous ice preparations 45 (1992) 15
Schmid, H., see Kreuzer 45 (1992) 381
Schmitz, A. and E. Van Cappellen, Influence of X-ray absorption on the spatial resolution of X-ray microanalysis of thin foils 45 (1992) 417
Shao, Z., see Yang 45 (1992) 199
Somlyo, A.P., see Yang 45 (1992) 199
Steeds, J.W., see Morniroli 45 (1992) 219

Tahara, Y., see Sakata 45 (1992) 253
Takayanagi, K., see Haga 45 (1992) 95
Takeyasu, K., see Yang 45 (1992) 199
Tencé, M., see Jeanguillaume 45 (1992) 205
Thust, A. and K. Urban, Quantitative high-speed matching of high-resolution electron microscopy images 45 (1992) 23
Tichelaar, W., see Trachtenberg 45 (1992) 307
Timsit, R.S., W.G. Waddington and C. Gallerneault, High-resolution electron microscopy of quasi-amorphous materials 45 (1992) 65
Tivol, W.F., see Dorset 45 (1992) 165
Trachtenberg, S., K.R. Leonard and W. Tichelaar, Radial mass density functions of vitrified helical specimens determined by scanning transmission electron microscopy: their potential use as substitutes for equatorial data 45 (1992) 307
Tsai, F. and J.M. Cowley, Observation of ferroelectric domain boundaries in $BaTiO_3$ single crystals by reflection electron microscopy 45 (1992) 43
Tsai, F., V. Khiznichenko and J.M. Cowley, High-resolution electron microscopy of 90° ferroelectric domain boundaries in $BaTiO_3$ and $Pb(Zr_{0.52}Ti_{0.48})O_3$ 45 (1992) 55
Turner, J.N., see Dorset 45 (1992) 165

Uchida, Y., see Wang 45 (1992) 291
Urban, K., see Thust 45 (1992) 23

Van Cappellen, E., see Schmitz 45 (1992) 417
Van der Biest, O., see Janssens 45 (1992) 323
Van Heel, M., see Schatz 45 (1992) 15
Vanhellemont, J., see Janssens 45 (1992) 323

Waddington, W.G., see Timsit 45 (1992) 65
Walsh, C.A., Effect of specimen bias on secondary electron images in the STEM 45 (1992) 85
Wang, N., Y. Uchida and G. Lehmpfuhl, Method of directly imaging the reconstruction on Au(111) and Au(100) by reflection electron microscoopy 45 (1992) 291

Wang, S.Q., L.-M. Peng, X.F. Duan and Y.M. Chu, Matrix description of dynamical HOLZ diffraction tested on the strained layer superlattice Si/GeSi 45 (1992) 405
Wang, Z., M. Moskovits and P. Rowntree, STM study of single crystal graphite 45 (1992) 337
Weiss, J.K., see Horita 45 (1992) 263
Wierzbicki, A., see Kreuzer 45 (1992) 381

Xu, P. and L.D. Marks, Intensities of surface diffraction spots in plan view 45 (1992) 155

Yang, J., K. Takeyasu, A.P. Somlyo and Z. Shao, Scanning tunneling microscopy of an ionic crystal: ferritin core 45 (1992) 199
Yokota, Y., see Li 45 (1992) 299

Zhou, F. and G. Möllenstedt, Convergent-beam electron diffraction pattern of muscovite and its computer simulation 45 (1992) 163
Zweck, J., see Mändl 45 (1992) 351

Ultramicroscopy 45 (1992) 435–437
North-Holland

ultramicroscopy

Subject index to volume 45

Analytical microscopy

Computer-assisted extrapolation method for absorption correction in quantitative X-ray microanalysis, *Horita, McCartney and Weiss* 45 (1992) 263

Influence of X-ray absorption on the spatial resolution of X-ray microanalysis of thin foils, *Schmitz and Van Cappellen* 45 (1992) 417

Cryomicroscopy

Invariant recognition of molecular projections in vitreous ice preparations, *Schatz and Van Heel* 45 (1992) 15

Limits of cryofixation as seen by Fourier transform infrared spectra of metmyoglobin azide and carbonyl hemoglobin in vitrified and freeze-concentrated aqueous solution, *Mayer and Astl* 45 (1992) 185

Radial mass density functions of vitrified helical specimens determined by scanning transmission electron microscopy: their potential use as substitutes for equatorial data, *Trachtenberg, Leonard and Tichelaar* 45 (1992) 307

Diffraction and optical diffraction

Direct phasing in electron crystallography: determination of layer silicate structures, *Dorset* 45 (1992) 5

Registry and UHV transmission electron diffraction of surfaces, *Marks* 45 (1992) 145

Intensities of surface diffraction spots in plan view, *Xu and Marks* 45 (1992) 155

Convergent-beam electron diffraction pattern of muscovite and its computer simulation, *Zhou and Möllenstedt* 45 (1992) 163

Electron crystallography at atomic resolution: ab initio structure analysis of copper perchlorophthalocyanine (*Erratum*), *Dorset, Tivol and Turner* 45 (1992) 165

Microdiffraction as a tool for crystal structure identification and determination, *Morniroli and Steeds* 45 (1992) 219

Sensitivity and accuracy of CBED pattern matching, *Bird and Saunders* 45 (1992) 241

SIMCON: a versatile software package for the simulation of electron diffraction contrast images of arbitrary displacement fields, *Janssens, Vanhellemont, De Graef and Van der Biest* 45 (1992) 323

Automated phase determination in electron crystallography: thermotropic phases of thiourea, *Dorset* 45 (1992) 357

Matrix description of dynamical HOLZ diffraction tested on the strained layer superlattice Si/GeSi, *Wang, Peng, Duan and Chu* 45 (1992) 405

Electron energy loss spectroscopy

Note on the energy lost by a charged particle specularly reflecting at a surface, *Barrachina and Gras-Marti* 45 (1992) 345

High resolution

Quantitative high-speed matching of high-resolution electron microscopy images, *Thust and Urban* 45 (1992) 23

High-resolution electron microscopy of 90° ferroelectric domain boundaries in $BaTiO_3$ and $Pb(Zr_{0.52}Ti_{0.48})O_3$, *Tsai, Khiznichenko and Cowley* 45 (1992) 55

High-resolution electron microscopy of quasi-amorphous materials, *Timsit, Waddington and Gallerneault* 45 (1992) 65

Single atom imaging in high-resolution UHV electron microscopy: Bi on Si(111) surface, *Haga and Takayanagi* 45 (1992) 95

On the iterative restoration of the exit plane wave function from defocus series in HREM, *Gribelyuk and Hutchison* 45 (1992) 127

Analytical description of image contrast in HRTEM and applications, *Geipel and Hohenstein* 45 (1992) 167

Phason-strain identification for quasicrystals by high-resolution electron microscopy, *Li, Pan, Huang, Hashimoto and Yokota* 45 (1992) 299

Holography

Electron holography in the study of the electrostatic fields: the case of charged microtips, *Matteucci, Missiroli, Muccini and Pozzi* 45 (1992) 77

Computer analysis of side-band holography in STEM, *Gribelyuk and Cowley* 45 (1992) 103

Determination of the imaging conditions in off-axis side-band STEM holography, *Gribelyuk and Cowley* 45 (1992) 115

Elsevier Science Publishers B.V.

Sideband holographic imaging of a tilt grain boundary to the 1.22 Å resolution level, *Krakow* 45 (1992) 269
Simulation and interpretation of STEM side-band holograms, *Konnert and D'Antonio* 45 (1992) 281
Theory of the point source electron microscope, *Kreuzer, Nakamura, Wierzbicki, Fink and Schmid* 45 (1992) 381

Image processing, 3D reconstruction
Invariant recognition of molecular projections in vitreous ice preparations, *Schatz and Van Heel* 45 (1992) 15
Quantitative high-speed matching of high-resolution electron microscopy images, *Thust and Urban* 45 (1992) 23
On the iterative restoration of the exit plane wave function from defocus series in HREM, *Gribelyuk and Hutchison* 45 (1992) 127
Convergent-beam electron diffraction pattern of muscovite and its computer simulation, *Zhou and Möllenstedt* 45 (1992) 163
Sideband holographic imaging of a tilt grain boundary to the 1.22 Å resolution level, *Krakow* 45 (1992) 269
Simulation and interpretation of STEM side-band holograms, *Konnert and D'Antonio* 45 (1992) 281
SIMCON: a versatile software package for the simulation of electron diffraction contrast images of arbitrary displacement fields, *Janssens, Vanhellemont, De Graef and Van der Biest* 45 (1992) 323

Imaging
Sideband holographic imaging of a tilt grain boundary to the 1.22 Å resolution level, *Krakow* 45 (1992) 269
Simulation and interpretation of STEM side-band holograms, *Konnert and D'Antonio* 45 (1992) 281

Methods and techniques
Device for direct writing and reading-out of information based on the scanning tunneling microscope, *Adamchuk and Ermakov* 45 (1992) 1
A method for observing cross-sectional views of biomembranes, *Sakata, Tahara, Morikawa, Fujiyoshi and Kimura* 45 (1992) 253
Computer-assisted extrapolation method for absorption correction in quantitative X-ray microanalysis, *Horita, McCartney and Weiss* 45 (1992) 263
Method of directly imaging the reconstruction on Au(111) and Au(100) by reflection electron microscoopy, *Wang, Uchida and Lehmpfuhl* 45 (1992) 291
Method for detection of thermally activated element migration inside multilayer metallizations by means of electron microscopy, *Mändl, Zweck and Hoffmann* 45 (1992) 351
Automated phase determination in electron crystallography: thermotropic phases of thiourea, *Dorset* 45 (1992) 357
Simple method for determining the absolute sense of image rotation in a transmission electron microscope, *Nakahara and Cullis* 45 (1992) 365

New developments
Electron crystallography at atomic resolution: ab initio structure analysis of copper perchlorophthalocyanine (*Erratum*), *Dorset, Tivol and Turner* 45 (1992) 165
New STEM multisignal imaging modes, made accessible through the evaluation of detection efficiencies, *Jeanguillaume, Colliex, Ballongue and Tencé* 45 (1992) 205
Microdiffraction as a tool for crystal structure identification and determination, *Morniroli and Steeds* 45 (1992) 219
Sensitivity and accuracy of CBED pattern matching, *Bird and Saunders* 45 (1992) 241
Two-dimensional demonstration of Wigner phase-retrieval microscopy in the STEM configuration, *McCallum and Rodenburg* 45 (1992) 371
Theory of the point source electron microscope, *Kreuzer, Nakamura, Wierzbicki, Fink and Schmid* 45 (1992) 381

Particle optics, theory
Optical properties and axial aberration coefficients of the cathode lens in combination with a focusing lens, *Lenc and Müllerová* 45 (1992) 159
Theory of the point source electron microscope, *Kreuzer, Nakamura, Wierzbicki, Fink and Schmid* 45 (1992) 381

Reflection electron microscopy, reflection high-energy electron diffraction
Observation of ferroelectric domain boundaries in $BaTiO_3$ single crystals by reflection electron microscopy, *Tsai and Cowley* 45 (1992) 43
Method of directly imaging the reconstruction on Au(111) and Au(100) by reflection electron microscoopy, *Wang, Uchida and Lehmpfuhl* 45 (1992) 291
Note on the energy lost by a charged particle specularly reflecting at a surface, *Barrachina and Gras-Marti* 45 (1992) 345

Scanning transmission electron microscopy

Effect of specimen bias on secondary electron images in the STEM, *Walsh* 45 (1992) 85

Computer analysis of side-band holography in STEM, *Gribelyuk and Cowley* 45 (1992) 103

Determination of the imaging conditions in off-axis side-band STEM holography, *Gribelyuk and Cowley* 45 (1992) 115

New STEM multisignal imaging modes, made accessible through the evaluation of detection efficiencies, *Jeanguillaume, Colliex, Ballongue and Tencé* 45 (1992) 205

Radial mass density functions of vitrified helical specimens determined by scanning transmission electron microscopy: their potential use as substitutes for equatorial data, *Trachtenberg, Leonard and Tichelaar* 45 (1992) 307

Two-dimensional demonstration of Wigner phase-retrieval microscopy in the STEM configuration, *McCallum and Rodenburg* 45 (1992) 371

Scanning tunneling microscopy

Device for direct writing and reading-out of information based on the scanning tunneling microscope, *Adamchuk and Ermakov* 45 (1992) 1

Scanning tunneling microscopy of an ionic crystal: ferritin core, *Yang, Takeyasu, Somlyo and Shao* 45 (1992) 199

STM study of single crystal graphite, *Wang, Moskovits and Rowntree* 45 (1992) 337

Specimen preparation

Preparation of TEM samples from compound semiconductors by chemomechanical polishing, *Sabinina and Gutakovsky* 45 (1992) 411

Surfaces, clusters, interfaces and particles

Observation of ferroelectric domain boundaries in $BaTiO_3$ single crystals by reflection electron microscopy, *Tsai and Cowley* 45 (1992) 43

High-resolution electron microscopy of 90° ferroelectric domain boundaries in $BaTiO_3$ and $Pb(Zr_{0.52}Ti_{0.48})O_3$, *Tsai, Khiznichenko and Cowley* 45 (1992) 55

Single atom imaging in high-resolution UHV electron microscopy: Bi on Si(111) surface, *Haga and Takayanagi* 45 (1992) 95

Registry and UHV transmission electron diffraction of surfaces, *Marks* 45 (1992) 145

Intensities of surface diffraction spots in plan view, *Xu and Marks* 45 (1992) 155

Method of directly imaging the reconstruction on Au(111) and Au(100) by reflection electron microscoopy, *Wang, Uchida and Lehmpfuhl* 45 (1992) 291

STM study of single crystal graphite, *Wang, Moskovits and Rowntree* 45 (1992) 337

Note on the energy lost by a charged particle specularly reflecting at a surface, *Barrachina and Gras-Marti* 45 (1992) 345

Method for detection of thermally activated element migration inside multilayer metallizations by means of electron microscopy, *Mändl, Zweck and Hoffmann* 45 (1992) 351

Matrix description of dynamical HOLZ diffraction tested on the strained layer superlattice Si/GeSi, *Wang, Peng, Duan and Chu* 45 (1992) 405

Abstracts / Announcements / Book reviews / Comments / Editorials / Reports

Novelties for the bookshelves, *Hawkes* 45 (1992) 421